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DESIGN OF DIGITAL
INSTRUMENTATION FOR
SCANNING PROBE MICROSCOPY

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Abstract

A scanning tunneling microscope with a focus on digital instrumentation has been built. The aim of this project was to allow a digital signal processor full control over all essential microscope variables, especially simultaneous control of the vertical and horizontal tip position.

Due to the fact that its operation is controlled by software, this system offers convenient operation and considerable flexibility, allowing different modes of operation, such as topographical and spectroscopic scans. Presently this microscope is the only one in New Zealand that allows the operator full software control over the tip position and bias voltage, thereby allowing it to become a powerful research tool.

Atomic scale images on graphite were successfully recorded. The spatial resolution of the microscope was estimated to be 5 pm vertically and 40 pm horizontally. Two different imaging methods were demonstrated on a gold sputtered TEM grating with a scan area that was larger than $4\ \mu\text{m} \times 4\ \mu\text{m}$. One method has variable horizontal scan speed, while the other method can possibly be used for nanolithography. Both show the flexibility of this system.

Although digital electronics is often perceived as being slower and noisier than analog electronics, in this instrument it did not decrease the data acquisition speed nor did it reduce the signal-to-noise ratio. The bandwidth of the closed-loop controlled microscope is currently about 1 kHz, limited by the bandwidth of the current-to-voltage converter, an analog component. The resolution is limited by the large gain of the high-voltage amplifiers used to drive the actuators. With a faster current-to-voltage converter and a reduced high-voltage amplifier gain, a bandwidth of 8 kHz should be possible with a vertical resolution of less than 2 pm and a horizontal resolution of 10 pm.

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Contents

Abstract	i
Acknowledgements	ii
List of Figures	viii
List of Tables	xi
1 Introduction	1
1.1 Scanning Probe Microscopy	1
1.1.1 Near-Field Microscopes	1
1.1.2 Short-Range Interaction	1
1.1.3 Image Generation	2
1.2 Computer Control for SPM	3
1.3 DSP-Controlled Microscope	5
1.3.1 Height Control	6
1.3.2 Spectroscopy	6
1.3.3 Convenient Service Tool	7
1.3.4 Position Control	7
1.3.5 Novel Imaging Modes and Nano-Manipulation	8
2 Probe Microscopy	9
2.1 Theoretical Background	9
2.1.1 One Dimensional Tunneling	9
2.1.2 Standard Model	12
2.2 General Design Considerations	18
2.3 Essentials for Scanning Probe Microscopy	20
2.3.1 Probe Head Overview	20
2.3.2 Microscope Overview	24
2.3.3 Operation of the Microscope	26
3 Mechanics	29
3.1 Moving the Microscope and the Scanning Tip	29
3.1.1 Piezoelectric Effect	29
3.1.2 Piezoelectric Actuators	36
3.1.3 Movement of the Probe Head	43
3.2 STM Tip	47
3.2.1 Tip Material	48
3.2.2 Tip Production	48

3.3	Vibration Isolation	54
3.3.1	Necessity of Vibration Isolation	54
3.3.2	Simple Spring-Mass System	54
3.3.3	Transmissibility	56
3.3.4	Air Table and Damping Stack	59
3.3.5	Vibrational Modes of Probe Head and Central Actuator	60
3.3.6	Conclusion	63
3.3.7	Horizontal Ringing	65
3.4	Thermal Compensation	66
4	Control	71
4.1	Microscope as a Control System	71
4.2	Feedback Control	71
4.2.1	Stability	73
4.2.2	Bandwidth	74
4.3	Direct Digital Control	75
4.3.1	Aliasing	76
4.3.2	Zero Order Hold	76
4.3.3	Quantization	77
4.4	Bandwidth of Sampled-Data Systems	77
4.4.1	Reconstruction	79
4.5	Microscope Control	81
4.6	Imaging Modes	83
5	Electronics	84
5.1	Design Specifications	84
5.1.1	Speed	84
5.1.2	Noise, Resolution and Dynamic Range Considerations	84
5.1.3	Tunneling Current	86
5.1.4	Piezoelectric Control Voltages	87
5.1.5	Bias Voltage	88
5.1.6	Input Channel	89
5.1.7	Data Transfer	90
5.1.8	Accuracy	91
5.2	Physical Organization of the Electronic Hardware	93
5.2.1	Modularity	93
5.2.2	Organization	93
5.3	DSP System	95
5.3.1	DSP	95
5.3.2	DSP System Interface	95
5.3.3	Overview of the DSP System Interface	100
5.3.4	Buffer, Address Decoding and Clock	102
5.3.5	Conversion between Parallel and Serial Data	102
5.4	Probe Electronics	110
5.4.1	Overview	110
5.4.2	IVC Module	111
5.4.3	Future Options	127
5.4.4	IVC Module Noise	127
5.4.5	ADC module	132
5.4.6	HV module	140

5.4.7	Bias Module	149
5.4.8	The Switchboard	151
6	Software	152
6.1	Overview	152
6.2	Programming the DSP	153
6.2.1	Programming	153
6.2.2	Processor	153
6.3	DSP Main Program	154
6.3.1	Single Program Approach	154
6.3.2	Polling	154
6.3.3	Main Routine	154
6.3.4	Output to Probe Electronics	156
6.3.5	Data Transfer	157
6.3.6	Tasks	157
6.4	Approach	158
6.4.1	Step	158
6.4.2	Detach	158
6.4.3	Find	161
6.5	Sample Investigation	161
6.5.1	Raster Scan	161
6.5.2	Linescan	163
6.5.3	Acquisition Methods	163
6.5.4	Characteristic Curves	168
6.6	Step Response	168
6.7	PC Program	168
6.7.1	PC Main Routine	168
6.7.2	Raster Scan	171
6.8	Image Display	171
6.9	Control Algorithm	173
6.9.1	PID Control	173
6.9.2	Discretization	173
6.9.3	Predictor Type Controller	177
6.9.4	Software Control	179
6.9.5	Parameter Tuning	180
6.9.6	Outlook	181
7	System	182
7.1	Introduction	182
7.2	System Speed	182
7.2.1	System Dead Time	182
7.2.2	Measured Response Time	183
7.2.3	Modeled Bandwidth	186
7.3	Step Size of Tip-Sample Approach	188
7.3.1	Automatic Approach	188
7.3.2	Approach Speed	189
7.3.3	Total Approach Time	193
7.3.4	Approach Speed of Second Method	193
7.3.5	Recorded Tip-Sample Approach	194
7.4	Scan Methods	196

7.4.1	Scan Speed	196
7.4.2	Choosing an Acquisition Method	198
7.5	System Noise	199
7.5.1	Input Signal Noise	199
7.5.2	HV and Bias Module Noise	202
7.5.3	System Signal-to-Noise Ratio	203
8	Experiments	206
8.1	Characteristic Curves	206
8.1.1	<i>I-s</i> Curve	206
8.1.2	<i>I-V</i> Curve	206
8.2	Raster Scan Images	209
8.3	TEM Grid	209
8.3.1	Incremental Method	209
8.3.2	Pogo Method	210
8.4	Graphite	210
8.4.1	Interpretation	212
8.4.2	Image Size and Corrugation	215
8.4.3	Noise Filtering	215
8.4.4	Terraces on Graphite	217
9	Summary and Conclusion	219
9.1	Summary	219
9.1.1	Mechanics	219
9.1.2	Electronics	220
9.1.3	Experimental Results	221
9.2	Conclusion	222
A	Mechanics	223
A.1	Piezoelectric Actuator Properties	223
A.2	Silver as an Electrode Material	223
A.3	Capacity of the Actuator	225
A.4	Sensitivity of the Actuators	226
A.4.1	Vertical Sensitivity	226
A.4.2	Horizontal Sensitivity	227
A.5	Vibrational Modes	232
A.5.1	Vibrational Modes of the Actuators	232
A.5.2	Longitudinal Vibration	233
A.5.3	Transverse Vibration	237
A.5.4	Vibration of the Probe Head	238
A.5.5	Beam Vibration	241
A.6	Thermal Drift of the STM	242
B	Electronics	246
B.0.1	Cascading Shift Registers	246
B.0.2	Pulse Stretcher	246
B.0.3	Communication Protocol	248
B.0.4	Switchboard Connections	249
B.1	Probe Electronics	250
B.1.1	Amplifier Noise Calculation	250

B.1.2	Noise Bandwidth	253
B.1.3	Step Rise Time	254
B.1.4	Choosing Optimum Gain	256
B.1.5	Sallen-Key Low-Pass Filters	257
B.2	Inverting Operational Amplifier	261
B.2.1	Voltage Signal Gain	261
B.2.2	Real Amplifier	262
B.2.3	Noise Gain	264
B.2.4	Transimpedance	265
B.2.5	Amplifier Voltage Noise	266
B.2.6	Future Options	268
B.2.7	T-Network	272
B.3	Logarithmic Conversion	275
B.3.1	Signal Rectifier	275
B.3.2	Transconductance Amplifier	275
B.3.3	Logarithmic Converter	277
B.3.4	Reference Current	279
C	Software	283
D	Circuits	286

List of Figures

1.1	Image Acquisition Modes	2
1.2	Scanning Probe Microscope	3
1.3	Interaction between PC, DSP and Probe Head	6
2.1	Energy Levels of Two Metals	10
2.2	Energy Levels	10
2.3	Standard Model	14
2.4	Sinusoidal Sample Model	14
2.5	Field Emission	16
2.6	Probe Head	19
2.7	Zeiss Probe Head	19
2.8	Tip and Sample	21
2.9	Piezoelectric Actuator Tube	22
2.10	Beetle-type Probe Head	23
2.11	Overview of the Scanning Tunneling Microscope	24
2.12	Coarse Approach Ramp	25
2.13	SPM System	25
3.1	Block of Piezoelectric Material	30
3.2	Creep of Center Actuator	35
3.3	Polarization of the Ceramic	36
3.4	Center Actuator	38
3.5	Outer Actuator	39
3.6	Double-Piezoelectric Effect (y)	42
3.7	Double-Piezoelectric Effect (x)	43
3.8	Typical Step Size	44
3.9	Calibration of the Probe Head	45
3.10	Tip Production	49
3.11	Electrochemically Etched Tips	51
3.12	Crashed Tip	52
3.13	Transmissibility	64
3.14	Induced Ringing	65
3.15	Power Spectrum of Ringing	66
3.16	Dimensions and Materials of Probe Head and Sample Holder	67
3.17	Measured Thermal Drift	69
4.1	Control Loop	72
4.2	Gain Margin	75
4.3	Sinc Function	79

4.4	Reaction Time	81
4.5	Feedback Control Loop of the STM System	82
5.1	System Overview	85
5.2	Electronic Hardware	93
5.3	Block diagram of the DSP system interface	100
5.4	Block diagram of the Buffer, Decoder and Clock	103
5.5	SPC and PSCs	104
5.6	Serial-to-Parallel Converter	106
5.7	Parallel-to-Serial Converter	108
5.8	Parallel-Data Register	109
5.9	Transimpedance Amplifier and Source Model	111
5.10	Transimpedance Amplifier with Parasitic Capacitances	116
5.11	Noise Model for the Transimpedance Amplifier	117
5.12	Superposition Principle	119
5.13	Measured and Modeled Frequency Response	121
5.14	Measured and Modeled Frequency Response	122
5.15	Signal, Noise and Open-loop Gain	125
5.16	Signal, Noise and Open-loop Gain	126
5.17	Signal-to-Noise-Ratio of Current-to-Voltage Converter (66 pF)	129
5.18	Signal-to-Noise-Ratio of Current-to-Voltage Converter (5 pF)	130
5.19	ADC Module	132
5.20	Switched Capacitor Network	134
5.21	HV Module	140
5.22	High-Voltage Amplifier	143
5.23	Bias Module	149
6.1	Software	153
6.2	Main Routine	155
6.3	Execution of a Task	157
6.4	Approach	158
6.5	Step	159
6.6	Detach	160
6.7	Find	161
6.8	Raster Scan	162
6.9	Linescan	163
6.10	Recording Tunneling Current	164
6.11	Point to Point Movement	166
6.12	Moving Trajectories	166
6.13	Settling Options	167
6.14	Step Response	169
6.15	PC Main Routine	170
6.16	Alternating Two Tasks	172
7.1	Direct Step Response	184
7.2	Step Response via IVC	185
7.3	Simulated System Response, Gain	187
7.4	Simulated System Response, Phase	188
7.5	Tunneling Current on Approach	194
7.6	Tunneling Current on Approach (Overview)	195

7.7	Slope	197
7.8	Calculated Noise of Input Channel	200
7.9	Signal-to-Noise Ratio of Current-To-Voltage Converter and ADC Module	201
7.10	Total Noise of the System	204
8.1	I - s Curve	207
8.2	Apparent Barrier Height Curve	208
8.3	I - V Curves	209
8.4	TEM Grating	211
8.5	TEM Grating, SEM image	212
8.6	Grid Imaged with Pogo Method	213
8.7	Limits of Actuator Range	213
8.8	Graphite	214
8.9	Graphite Structure	214
8.10	Tip Change and Close-up	216
8.11	2D Fourier Transformation of Graphite Image	217
8.12	Terraces on Graphite	218
8.13	Single Terrace on Graphite	218
A.1	Horizontal Actuator Deflection	228
B.1	Pulse Stretcher Circuit	247
B.2	Pulse Tagger Circuit	247
B.3	Step Response of two RC low-pass filters	255
B.4	Sallen-Key Bessel Low-Pass Filter	257
B.5	Inverting Operational Amplifier	261
B.6	Amplifier Voltage Noise	269
B.7	Amplifier Voltage Noise	270
B.8	T-Network	272
B.9	Noise Control T-Network	274
B.10	Compensation Network	274
B.11	Transconductance Amplifier	276
B.12	Logarithmic Converter	277
B.13	Reference Current	280

List of Tables

2.1	Tip-Sample Approach	21
3.1	Measured Capacitance of Quadrants	41
3.2	Measured Longitudinal Resonance Frequencies	61
5.1	Low Bias Current Operational Amplifiers	114
7.1	Time Constants	186
7.2	Measured and Calculated Input Channel Noise	202
7.3	Measured Noise of HV and Bias Module	203
A.1	Properties of the Center Actuator	224
A.2	Properties of the Outer Actuators	224
A.3	Effective speed of sound in center actuator	234
A.4	Natural Frequencies of the Probe Head	241
A.5	Thermal Expansion Coefficients	243
A.6	Thermal Expansion of the STM	245
B.1	Operational Amplifier Noise	250
B.2	Estimate and Comparison of Time Constants	255
B.3	Gain Values for Sallen-Key Low-Pass Filter	258
B.4	Frequency Values for Sallen-Key Low-Pass Filter	259